

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of Applicants:	Date: June 1, 2007
B. S. Beaman et al.	Group Art Unit: 2829
Serial No.: 10/145,661	Examiner: J. M. Hollington
Filed: May 14, 2002	Docket No.: YOR919990088US1
For: STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE POSITION ACCURACY IN A WAFER TEST PROBE ASSEMBLY	

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**RESPONSE TO OFFICE ACTION DATED MARCH 1, 2007**

Sir:

In response to the Office Action dated March 1, 2007, please amend the above-identified application as follows:

Remarks begin on page 2 of this paper.